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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

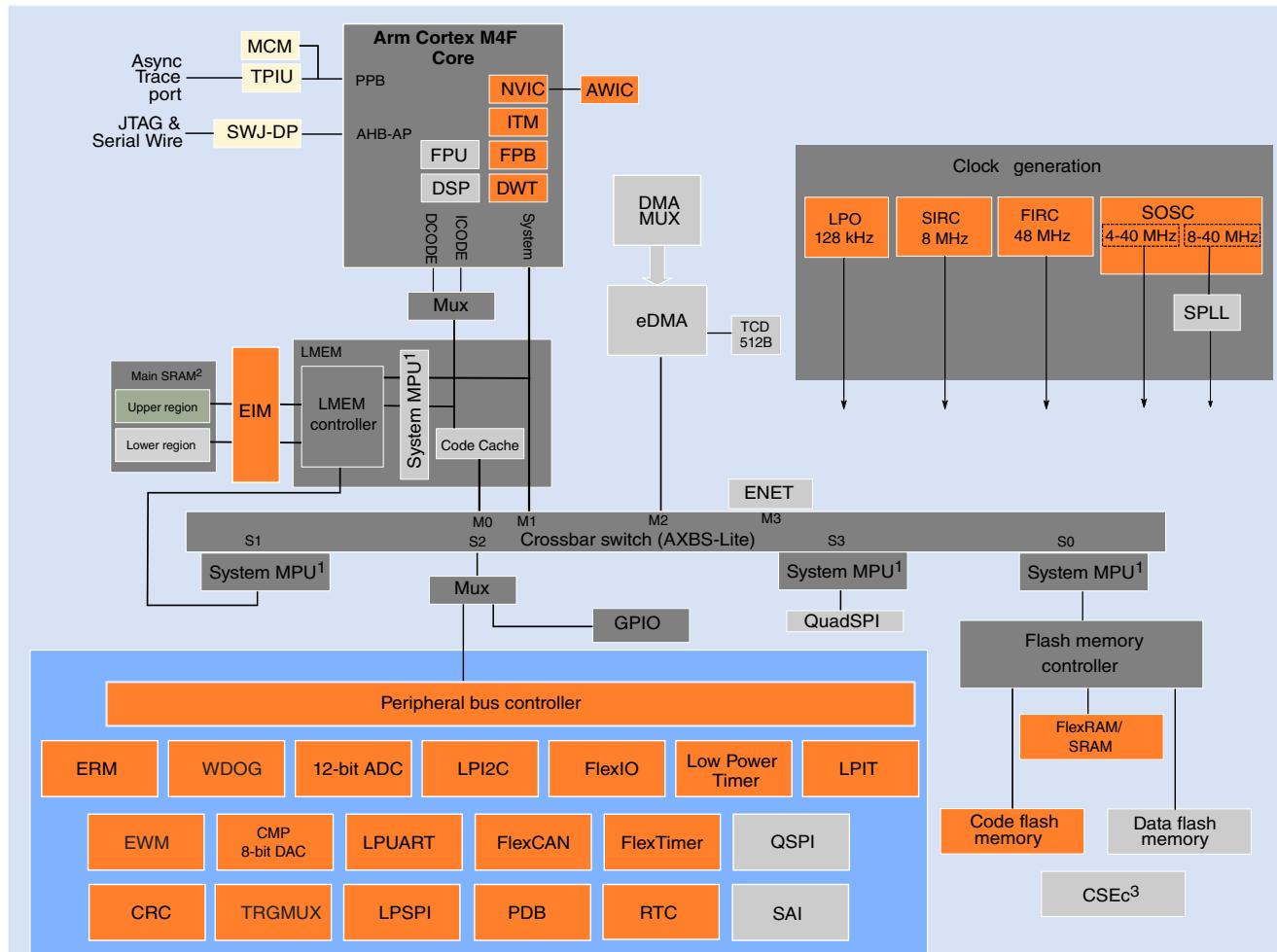
Details

Product Status	Active
Core Processor	ARM® Cortex®-M4F
Core Size	32-Bit Single-Core
Speed	64MHz
Connectivity	CANbus, FlexIO, I²C, LINbus, SPI, UART/USART
Peripherals	POR, PWM, WDT
Number of I/O	58
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 16x12b SAR; D/A1x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/fs32k144mat0vlhr

- Communications interfaces
 - Up to three Low Power Universal Asynchronous Receiver/Transmitter (LPUART/LIN) modules with DMA support and low power availability
 - Up to three Low Power Serial Peripheral Interface (LPSPI) modules with DMA support and low power availability
 - Up to two Low Power Inter-Integrated Circuit (LPI2C) modules with DMA support and low power availability
 - Up to three FlexCAN modules (with optional CAN-FD support)
 - FlexIO module for emulation of communication protocols and peripherals (UART, I2C, SPI, I2S, LIN, PWM, etc).
 - Up to one 10/100Mbps Ethernet with IEEE1588 support and two Synchronous Audio Interface (SAI) modules.
- Safety and Security
 - Cryptographic Services Engine (CSEc) implements a comprehensive set of cryptographic functions as described in the SHE (Secure Hardware Extension) Functional Specification. Note: CSEc (Security) or EEPROM writes/erase will trigger error flags in HSRUN mode (112 MHz) because this use case is not allowed to execute simultaneously. The device will need to switch to RUN mode (80 MHz) to execute CSEc (Security) or EEPROM writes/erase.
 - 128-bit Unique Identification (ID) number
 - Error-Correcting Code (ECC) on flash and SRAM memories
 - System Memory Protection Unit (System MPU)
 - Cyclic Redundancy Check (CRC) module
 - Internal watchdog (WDOG)
 - External Watchdog monitor (EWM) module
- Timing and control
 - Up to eight independent 16-bit FlexTimers (FTM) modules, offering up to 64 standard channels (IC/OC/PWM)
 - One 16-bit Low Power Timer (LPTMR) with flexible wake up control
 - Two Programmable Delay Blocks (PDB) with flexible trigger system
 - One 32-bit Low Power Interrupt Timer (LPIT) with 4 channels
 - 32-bit Real Time Counter (RTC)
- Package
 - 32-pin QFN, 48-pin LQFP, 64-pin LQFP, 100-pin LQFP, 100-pin MAPBGA, 144-pin LQFP, 176-pin LQFP package options
- 16 channel DMA with up to 63 request sources using DMAMUX

1 Block diagram

Following figures show superset high level architecture block diagrams of S32K14x series and S32K11x series respectively. Other devices within the family have a subset of the features. See [Feature comparison](#) for chip specific values.



1: On this device, NXP's system MPU implements the safety mechanisms to prevent masters from accessing restricted memory regions. This system MPU provides memory protection at the level of the Crossbar Switch. Each Crossbar master (Core, DMA, Ethernet) can be assigned different access rights to each protected memory region. The Arm M4 core version in this family does not integrate the Arm Core MPU, which would concurrently monitor only core-initiated memory accesses. In this document, the term MPU refers to NXP's system MPU.

2: For the device-specific sizes, see the "On-chip SRAM sizes" table in the "Memories and Memory Interfaces" chapter of the S32K1xx Series Reference Manual.

3: CSEc (Security) or EEPROM writes/erase will trigger error flags in HSRUN mode (112 MHz) because this use case is not allowed to execute simultaneously. The device need to switch to RUN mode (80 MHz) to execute CSEc (Security) or EEPROM writes/erase.

Key:

Device architectural IP on all S32K devices
Peripherals present on all S32K devices
Peripherals present on selected S32K devices (see the "Feature Comparison" section)

Figure 1. High-level architecture diagram for the S32K14x family

Feature comparison

Description Input Multiplexing sheet(s) attached with Reference Manual.

	S32K11x		S32K14x				
Parameter	K116	K118	K142	K144	K146	K148	
Core	Arm® Cortex™-M0+		Arm® Cortex™-M4F				
Frequency	48 MHz		80 MHz (RUN mode) or 112 MHz (HSRUN mode) ¹				
System	IEEE-754 FPU	○			●		
	Cryptographic Services Engine (CSEc) ¹	●			●		
	CRC module	1x			1x		
	ISO 26262	capable up to ASIL-B		capable up to ASIL-B			
	Peripheral speed	up to 48 MHz		up to 112 MHz (HSRUN)			
	Crossbar	●			●		
	DMA	●			●		
	External Watchdog Monitor (EWM)	○			●		
	Memory Protection Unit (MPU)	●			●		
	FIRC CMU	●			○		
	Watchdog	1x			1x		
	Low power modes	●			●		
	HSRUN mode ¹	○			●		
Memory	Number of I/Os	up to 43	up to 58	up to 89	up to 128	up to 156	
	Single supply voltage	2.7 - 5.5 V		2.7 - 5.5 V			
	Ambient Operation Temperature (Ta)	-40°C to +105°C / +125°C		-40°C to +105°C / +125°C			
	Flash	128 KB	256 KB	256 KB	512 KB	1 MB	2 MB ²
	Error Correcting Code (ECC)	●			●		
	System RAM (including FlexRAM and MTB)	17 KB	25 KB	32 KB	64 KB	128 KB	256 KB
	FlexRAM (also available as system RAM)	2 KB		4 KB			
Timer	Cache	○			4 KB		
	EEPROM emulated by FlexRAM ¹	2 KB (up to 32 KB D-Flash)		4 KB (up to 64 KB D-Flash)			See footnote 3
	External memory interface	○		○			QuadSPI incl. HyperBus TM
	Low Power Interrupt Timer (LPIT)	1x			1x		
	FlexTimer (16-bit counter) 8 channels	2x (16)		4x (32)	6x (48)	8x (64)	
Analog	Low Power Timer (LPTMR)	1x			1x		
	Real Time Counter (RTC)	1x			1x		
	Programmable Delay Block (PDB)	1x			2x		
	Trigger mux (TRGMUX)	1x (43)	1x (45)	1x (64)	1x (73)	1x (81)	
Communication	12-bit SAR ADC (1 Msps each)	1x (13)	1x (16)	2x (16)	2x (24)	2x (32)	
	Comparator with 8-bit DAC	1x			1x		
	10/100 Mbps IEEE-1588 Ethernet MAC	○		○		1x	
	Serial Audio Interface (AC97, TDM, I2S)	○		○		2x	
	Low Power UART/LIN (LPUART) (Supports LIN protocol versions 1.3, 2.0, 2.1, 2.2A, and SAE J2602)	2x		2x	3x		
	Low Power SPI (LPSPI)	1x	2x	2x	3x		
	Low Power I2C (LPI2C)	1x			1x		2x
IDEs	FlexCAN (CAN-FD ISO/CD 11898-1)	1x (1x with FD)		2x (1x with FD)	3x (1x with FD)	3x (2x with FD)	3x (3x with FD)
	FlexIO (8 pins configurable as UART, SPI, I2C, I2S)	1x		1x			
Other	Debug & trace	SWD, MTB (1 KB), JTAG ⁴		SWD, JTAG (ITM, SWV, SWO)			SWD, JTAG (ITM, SWV, SWO), ETM
	Ecosystem (IDE, compiler, debugger)	NXP S32 Design Studio (GCC) + SDK, IAR, GHS, Arm®, Lauterbach, iSystems		NXP S32 Design Studio (GCC) + SDK, IAR, GHS, Arm®, Lauterbach, iSystems			
Packages ⁵	32-pin QFN 48-pin LQFP	48-pin LQFP 64-pin LQFP	64-pin LQFP 100-pin LQFP	64-pin LQFP 100-pin LQFP 100-pin MAPBGA 144-pin LQFP	64-pin LQFP 100-pin MAPBGA 100-pin LQFP 144-pin LQFP	64-pin LQFP 100-pin MAPBGA 100-pin LQFP 144-pin LQFP	100-pin MAPBGA 144-pin LQFP 176-pin LQFP

LEGEND:

- Not implemented
 - Available on the device
- 1 No write or erase access to Flash module, including Security (CSEc) and EEPROM commands, are allowed when device is running at HSRUN mode (112MHz) or VLPR mode.
- 2 Available when EEPROM, CSEc and Data Flash are not used. Else only up to 1,984 KB is available for Program Flash.
- 3 4 KB (up to 512 KB D-Flash as a part of 2 MB Flash). Up to 64 KB of flash is used as EEPROM backup and the remaining 448 KB of the last 512 KB block can be used as Data flash or Program flash. See chapter FTFC for details.
- 4 Only for Boundary Scan Register
- 5 See Dimensions section for package drawings

Figure 3. S32K1xx product series comparison

4 General

4.1 Absolute maximum ratings

NOTE

- Functional operating conditions appear in the DC electrical characteristics. Absolute maximum ratings are stress ratings only, and functional operation at the maximum values is not guaranteed. See footnotes in the following table for specific conditions.
- Stress beyond the listed maximum values may affect device reliability or cause permanent damage to the device.
- All the limits defined in the datasheet specification must be honored together and any violation to any one or more will not guarantee desired operation.
- Unless otherwise specified, all maximum and minimum values in the datasheet are across process, voltage, and temperature.

Table 1. Absolute maximum ratings

Symbol	Parameter	Conditions ¹	Min	Max	Unit
V_{DD} ²	2.7 V - 5.5V input supply voltage	—	-0.3	5.8 ³	V
V_{REFH}	3.3 V / 5.0 V ADC high reference voltage	—	-0.3	5.8 ³	V
$I_{INJPAD_DC_ABS}$ ⁴	Continuous DC input current (positive / negative) that can be injected into an I/O pin	—	-3	+3	mA
V_{IN_DC}	Continuous DC Voltage on any I/O pin with respect to V_{SS}	—	-0.8	5.8 ⁵	V
$I_{INJSUM_DC_ABS}$	Sum of absolute value of injected currents on all the pins (Continuous DC limit)	—	—	30	mA
T_{ramp} ⁶	ECU supply ramp rate	—	0.5 V/min	500 V/ms	—
T_{ramp_MCU} ⁷	MCU supply ramp rate	—	0.5 V/min	100 V/ms	—
T_A ⁸	Ambient temperature	—	-40	125	°C
T_{STG}	Storage temperature	—	-55	165	°C
$V_{IN_TRANSIENT}$	Transient overshoot voltage allowed on I/O pin beyond V_{IN_DC} limit	—	—	6.8 ⁹	V

1. All voltages are referred to V_{SS} unless otherwise specified.
2. As V_{DD} varies between the minimum value and the absolute maximum value the analog characteristics of the I/O and the ADC will both change. See section [I/O parameters](#) and [ADC electrical specifications](#) respectively for details.
3. 60 s lifetime – No restrictions i.e. The part can switch.

10 hours lifetime – Device in reset i.e. The part cannot switch.

Table 5. V_{DD} supply LVR, LVD and POR operating requirements (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V _{LVW}	Falling low-voltage warning threshold	4.19	4.305	4.5	V	
V _{LVW_HYST}	LVW hysteresis	—	75	—	mV	1
V _{BG}	Bandgap voltage reference	0.97	1.00	1.03	V	

1. Rising threshold is the sum of falling threshold and hysteresis voltage.

4.6 Power mode transition operating behaviors

All specifications in the following table assume this clock configuration:

- RUN Mode:
 - Clock source: FIRC
 - SYS_CLK/CORE_CLK = 48 MHz
 - BUS_CLK = 48 MHz
 - FLASH_CLK = 24 MHz
- HSRUN Mode:
 - Clock source: PLL
 - SYS_CLK/CORE_CLK = 112 MHz
 - BUS_CLK = 56 MHz
 - FLASH_CLK = 28 MHz
- VLPR Mode:
 - Clock source: SIRC
 - SYS_CLK/CORE_CLK = 4 MHz
 - BUS_CLK = 4 MHz
 - FLASH_CLK = 1 MHz
- STOP1/STOP2 Mode:
 - Clock source: FIRC
 - SYS_CLK/CORE_CLK = 48 MHz
 - BUS_CLK = 48 MHz
 - FLASH_CLK = 24 MHz
- VLPS Mode: All clock sources disabled ¹

Table 6. Power mode transition operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit
t _{POR}	After a POR event, amount of time from the point V _{DD} reaches 2.7 V to execution of the first instruction across the operating temperature range of the chip.	—	325	—	μs

Table continues on the next page...

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1. • For S32K11x – FIRC/SOSC
• For S32K14x – FIRC/SOSC/PLL

Table 7. Power consumption (Typicals unless stated otherwise) 1 (continued)

Chip/Device	Ambient Temperature (°C)	VLPS (µA) ²		VLPR (mA)			STOP1 (mA)	STOP2 (mA)	RUN@48 MHz (mA)		RUN@64 MHz (mA)		RUN@80 MHz (mA)		HSRUN@112 MHz (mA) ³		General IDDMHz (µA/MHz) ⁴	
		Peripherals disabled ⁵	Peripherals enabled	Peripherals disabled ⁶	Peripherals enabled use case 1 ⁶	Peripherals enabled use case 2 ⁷			Peripherals disabled	Peripherals enabled	Peripherals disabled	Peripherals enabled	Peripherals disabled	Peripherals enabled	Peripherals disabled	Peripherals enabled		
		Max	1637	1694	3.1	3.21	NA	12.7	13.7	25	32.9	30.7	38.8	36	43.8	NA	450	
S32K144	25	Typ	29.8	42	1.48	1.50	2.91	7	7.7	19.7	26.9	25.1	33.3	30.2	39.6	43.3	55.6	378
	85	Typ	150	159	1.72	1.85	3.08	7.2	8.1	20.4	27.1	26.1	33.5	30.5	40	43.9	56.1	381
		Max	359	384	2.60	2.65	NA	9.2	9.9	23.2	29.6	29.3	36.2	34.8	42.1	46.3	59.7	435
	105	Typ	256	273	1.80	2.10	3.23	7.8	8.5	20.6	27.4	26.6	33.8	31.2	40.5	44.8	57.1	390
		Max	850	900	2.65	2.70	NA	10.3	11.1	23.9	30.6	30.3	37.3	35.6	43.5	47.9	61.3	445
	125	Typ	NA	NA	NA	NA	3.65	NA	NA	NA	NA	NA	NA	NA	NA	NA	NA	
		Max	1960	1998	3.18	3.25	NA	12.9	13.8	26.9	33.6	35	40.3	38.7	46.8	NA	NA	484
S32K146	25	Typ	37	47	1.57	1.61	3.3	8	9.2	23.4	31.4	30.5	40.2	36.2	47.6	52	68.3	452
	85	Typ	207	209	1.79	1.83	3.54	8.9	10.1	24.4	32.4	31.5	41.3	37.2	48.7	53.3	69.8	465
		Max	974	981	3.32	3.38	NA	12.7	13.9	29.3	37.9	36.7	47	42.4	54.4	60.3	78	530
	105	Typ	419	422	1.99	2.04	3.78	9.8	11	25.3	33.4	32.5	42.2	38.1	49.6	54.4	70.8	477
		Max	2004	2017	4.06	4.13	NA	17.1	18.3	34.1	42.6	41.3	51.4	46.9	58.8	65.7	82.8	587
	125	Typ	NA	NA	NA	NA	4.44	NA	NA	NA	NA	NA	NA	NA	NA	NA	NA	
		Max	3358	3380	5.28	5.38	NA	22.6	23.7	40.2	48.8	47.3	57.4	52.8	64.8	NA	NA	660
S32K148 ⁸	25	Typ	38	54	2.17	2.20	3.45	8.5	9.6	27.6	34.9	35.5	45.3	42.1	57.7	60.3	83.3	526
	85	Typ	336	357	2.30	2.35	3.74	10.1	11.1	29.1	37.0	36.8	46.6	43.4	59.9	62.9	88.7	543

Table continues on the next page...

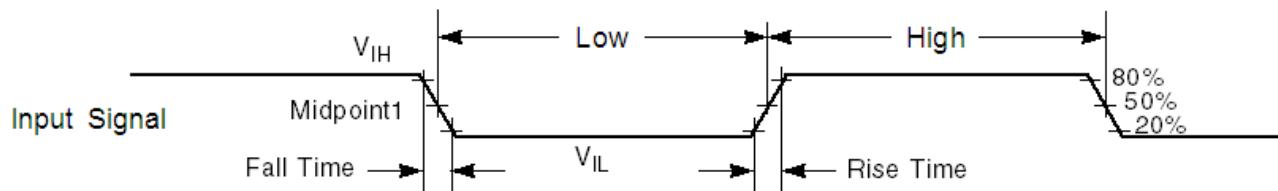
Table 8. VLPS additional use-case power consumption at typical conditions

Use-case	Description	Temp.	Device						Unit
			S32K116	S32K118	S32K142	S32K144	S32K146	S32K148	
VLPS and RTC	<ul style="list-style-type: none"> Clock source: LPO or RTC_CLKIN 	25	TBD	TBD	30	30	30	40	µA
		85	TBD	TBD	110	170	180	240	µA
		105	TBD	TBD	230	330	350	490	µA
		125	TBD	TBD	570	680	810	1250	µA
VLPS and LPUART TX/RX	<ul style="list-style-type: none"> Clock source: SIRC Transmiting or receiving continuously using DMA Baudrate: 19.2 kbps 	25	TBD	TBD	230	230	250	250	µA
		85	TBD	TBD	320	400	410	490	µA
		105	TBD	TBD	490	550	600	850	µA
		125	TBD	TBD	890	1070	1250	1960	µA
VLPS and LPUART wake-up	<ul style="list-style-type: none"> Clock source: SIRC Wake-up address feature enabled Baudrate: 19.2 kbps 	25	TBD	TBD	100	100	110	110	µA
		85	TBD	TBD	170	240	280	350	µA
		105	TBD	TBD	260	400	480	600	µA
		125	TBD	TBD	530	580	1000	1280	µA
VLPS and LPI2C master	<ul style="list-style-type: none"> Clock Source: SIRC Transmit/receive using DMA Baudrate: 100 kHz 	25	TBD	TBD	670	690	820	900	µA
		85	TBD	TBD	880	960	1220	1370	µA
		105	TBD	TBD	1080	1250	1660	2060	µA
		125	TBD	TBD	1970	1980	2860	3690	µA
VLPS and LPI2C slave wake-up	<ul style="list-style-type: none"> Clock source: SIRC Wake-up address feature enabled Baudrate: 100 kHz 	25	TBD	TBD	250	250	270	280	µA
		85	TBD	TBD	340	340	410	510	µA
		105	TBD	TBD	430	430	610	810	µA
		125	TBD	TBD	740	760	1170	1540	µA
VLPS and LPSPI master	<ul style="list-style-type: none"> Clock source: SIRC Transmit/receive using DMA Baudrate: 500 kHz 	25	TBD	TBD	2.99	3.19	3.75	4.11	mA
		85	TBD	TBD	3.26	3.7	4.35	4.93	mA
		105	TBD	TBD	3.5	4.2	4.93	5.74	mA
		125	TBD	TBD	3.93	4.63	5.97	7.38	mA
VLPS and LPIT	<ul style="list-style-type: none"> Clock source: SIRC 1 channel enable Mode: 32-bit periodic counter 	25	TBD	TBD	100	100	120	130	µA
		85	TBD	TBD	190	250	260	320	µA
		105	TBD	TBD	310	410	440	570	µA
		125	TBD	TBD	640	750	910	1280	µA

5 I/O parameters

5.1 AC electrical characteristics

Unless otherwise specified, propagation delays are measured from the 50% to the 50% point, and rise and fall times are measured at the 20% and 80% points, as shown in the following figure.



The midpoint is $V_{IL} + (V_{IH} - V_{IL})/2$.

Figure 7. Input signal measurement reference

5.2 General AC specifications

These general purpose specifications apply to all signals configured for GPIO, UART, and timers.

Table 10. General switching specifications

Symbol	Description	Min.	Max.	Unit	Notes
	GPIO pin interrupt pulse width (digital glitch filter disabled) — Synchronous path	1.5	—	Bus clock cycles	1, 2
	GPIO pin interrupt pulse width (digital glitch filter disabled, passive filter disabled) — Asynchronous path	50	—	ns	3
WFRST	RESET input filtered pulse	—	10	ns	4
WNFRST	RESET input not filtered pulse	Maximum of (100 ns, bus clock period)	—	ns	5

1. This is the minimum pulse width that is guaranteed to pass through the pin synchronization circuitry. Shorter pulses may or may not be recognized. In Stop and VLPS modes, the synchronizer is bypassed so shorter pulses can be recognized in that case.
2. The greater of synchronous and asynchronous timing must be met.
3. These pins do not have a passive filter on the inputs. This is the shortest pulse width that is guaranteed to be recognized.
4. Maximum length of RESET pulse which will be filtered by internal filter.
5. Minimum length of RESET pulse, guaranteed not to be filtered by the internal filter. This number depends on bus clock period also. For example, in VLPR mode bus clock is 4 MHz, which make clock period of 250 ns. In this case, minimum pulse width which will cause reset is 250 ns. For faster bus clock frequencies which have clock period less than 100 ns, the minimum pulse width not filtered will be 100 ns.

**Table 17. External System Oscillator electrical specifications
(continued)**

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	High-gain mode (HGO=1)	—	1	—	MΩ	
R _S	Series resistor					3
	Low-gain mode (HGO=0)	—	0	—	kΩ	
	High-gain mode (HGO=1)	—	0	—	kΩ	
V _{pp}	Peak-to-peak amplitude of oscillation (oscillator mode)					3
	Low-gain mode (HGO=0)	—	1.0	—	V	
	High-gain mode (HGO=1)	—	3.3	—	V	

1. Crystal oscillator circuit provides stable oscillations when $g_{mXOSC} > 5 * gm_crit$. The gm_crit is defined as:

$$gm_crit = 4 * ESR * (2\pi F)^2 * (C_0 + C_L)^2$$

where:

- g_{mXOSC} is the transconductance of the internal oscillator circuit
- ESR is the equivalent series resistance of the external crystal
- F is the external crystal oscillation frequency
- C_0 is the shunt capacitance of the external crystal
- C_L is the external crystal total load capacitance. $C_L = C_s + [C_1 * C_2 / (C_1 + C_2)]$
- C_s is stray or parasitic capacitance on the pin due to any PCB traces
- C_1, C_2 external load capacitances on EXTAL and XTAL pins

See manufacture datasheet for external crystal component values

2.
 - When low-gain is selected, internal R_F will be selected and external R_F should not be attached.
 - When high-gain is selected, external R_F (1 M Ohm) needs to be connected for proper operation of the crystal. For external resistor, up to 5% tolerance is allowed.
3. The EXTAL and XTAL pins should only be connected to required oscillator components and must not be connected to any other devices.

6.2.2 External System Oscillator frequency specifications

Table 23. Flash command timing specifications for S32K14x (continued)

Symbol	Description ¹	S32K142		S32K144		S32K146		S32K148			
		Typ	Max	Typ	Max	Typ	Max	Typ	Max	Unit	Notes
t _{setram}	Set FlexRAM Function execution time	Control Code 0xFF	0.08	—	0.08	—	0.08	—	0.08	—	ms ³
		32 KB EEPROM backup	0.8	1.2	0.8	1.2	0.8	1.2	—	—	
		48 KB EEPROM backup	1	1.5	1	1.5	1	1.5	—	—	
		64 KB EEPROM backup	1.3	1.9	1.3	1.9	1.3	1.9	1.3	1.9	
t _{eewr8b}	Byte write to FlexRAM execution time	32 KB EEPROM backup	385	1700	385	1700	385	1700	—	—	μs ^{3·4}
		48 KB EEPROM backup	430	1850	430	1850	430	1850	—	—	
		64 KB EEPROM backup	475	2000	475	2000	475	2000	475	4000	
t _{eewr16b}	16-bit write to FlexRAM execution time	32 KB EEPROM backup	385	1700	385	1700	385	1700	—	—	μs ^{3·4}
		48 KB EEPROM backup	430	1850	430	1850	430	1850	—	—	
		64 KB EEPROM backup	475	2000	475	2000	475	2000	475	4000	
t _{eewr32bers}	32-bit write to erased FlexRAM location execution time	—	360	2000	360	2000	360	2000	360	2000	μs
t _{eewr32b}	32-bit write to FlexRAM execution time	32 KB EEPROM backup	630	2000	630	2000	630	2000	—	—	μs ^{3·4}
		48 KB EEPROM backup	720	2125	720	2125	720	2125	—	—	
		64 KB EEPROM backup	810	2250	810	2250	810	2250	810	4500	
t _{quickwr}	32-bit Quick Write execution time: Time from CCIF clearing (start the write) until CCIF	1st 32-bit write	200	550	200	550	200	550	200	1100	μs ^{4·5·6}
		2nd through Next to Last (Nth-1) 32-bit write	150	550	150	550	150	550	150	550	

Table continues on the next page...

Table 23. Flash command timing specifications for S32K14x (continued)

Symbol	Description ¹		S32K142		S32K144		S32K146		S32K148		Unit	Notes
			Typ	Max	Typ	Max	Typ	Max	Typ	Max		
	setting (32-bit write complete, ready for next 32-bit write)	Last (Nth) 32-bit write (time for write only, not cleanup)	200	550	200	550	200	550	200	550		
t _{quickwrClnup}	Quick Write Cleanup execution time	—	—	(# of Quick Writes) * 2.0	—	(# of Quick Writes) * 2.0	—	(# of Quick Writes) * 2.0	—	(# of Quick Writes) * 2.0	ms	⁷

1. All command times assumes 25 MHz or greater flash clock frequency (for synchronization time between internal/external clocks).
2. Maximum times for erase parameters based on expectations at cycling end-of-life.
3. For all EEPROM Emulation terms, the specified timing shown assumes previous record cleanup has occurred. This may be verified by executing FCCOB Command 0x77, and checking FCCOB number 5 contents show 0x00 - No EEPROM issues detected.
4. 1st time EERAM writes after a Reset or SETRAM may incur additional overhead for EEE cleanup, resulting in up to 2x the times shown.
5. Only after the Nth write completes will any data be valid. Emulated EEPROM record scheme cleanup overhead may occur after this point even after a brownout or reset. If power on reset occurs before the Nth write completes, the last valid record set will still be valid and the new records will be discarded.
6. Quick Write times may take up to 550 µs, as additional cleanup may occur when crossing sector boundaries.
7. Time for emulated EEPROM record scheme overhead cleanup. Automatically done after last (Nth) write completes, assuming still powered. Or via SETRAM cleanup execution command is requested at a later point.

Table 24. Flash command timing specifications for S32K11x

Symbol	Description ¹		S32K116		S32K118			
			Typ	Max	Typ	Max	Unit	Notes
t _{rd1blk}	Read 1 Block execution time	32 KB flash	—	0.36	—	0.36	ms	
		64 KB flash	—	—	—	—		
		128 KB flash	—	1.2	—	—		
		256 KB flash	—	—	—	2		
		512 KB flash	—	—	—	—		
t _{rd1sec}	Read 1 Section execution time	2 KB flash	—	75	—	75	µs	
		4 KB flash	—	100	—	100		
t _{pgmchk}	Program Check execution time	—	—	100	—	100	µs	
t _{pgm8}	Program Phrase execution time	—	90	225	90	225	µs	
t _{ersblk}	Erase Flash Block execution time	32 KB flash	15	300	15	300	ms	²
		64 KB flash	—	—	—	—		
		128 KB flash	120	1100	—	—		
		256 KB flash	—	—	250	2125		
		512 KB flash	—	—	—	—		

Table continues on the next page...

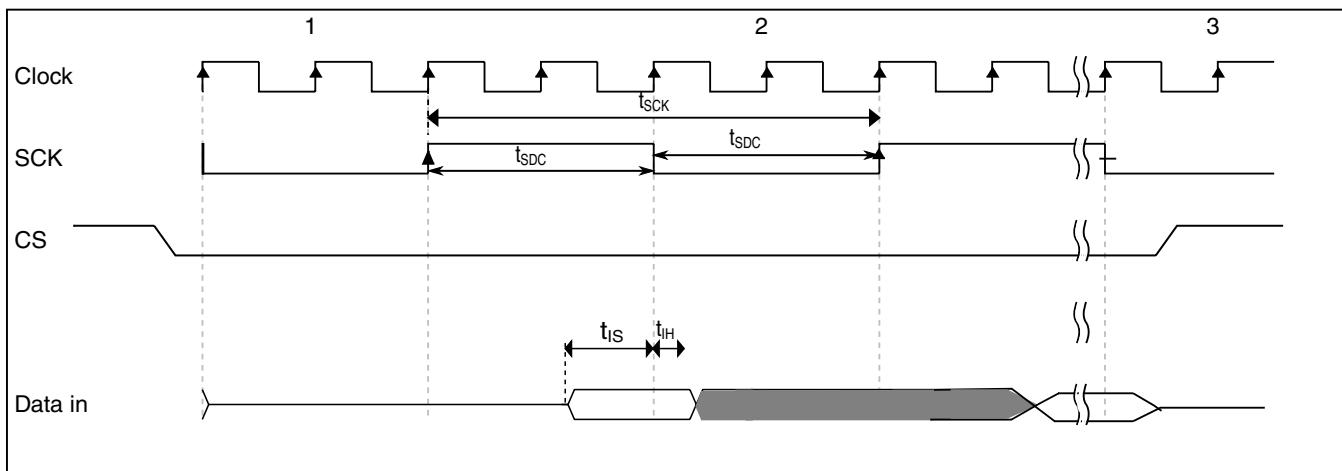


Figure 9. QuadSPI input timing (SDR mode) diagram

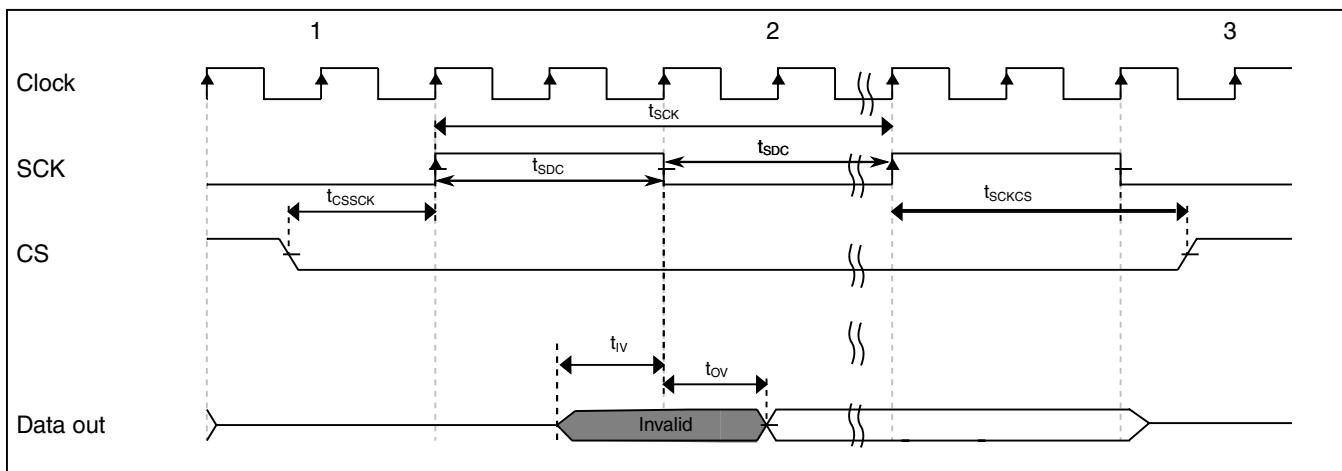
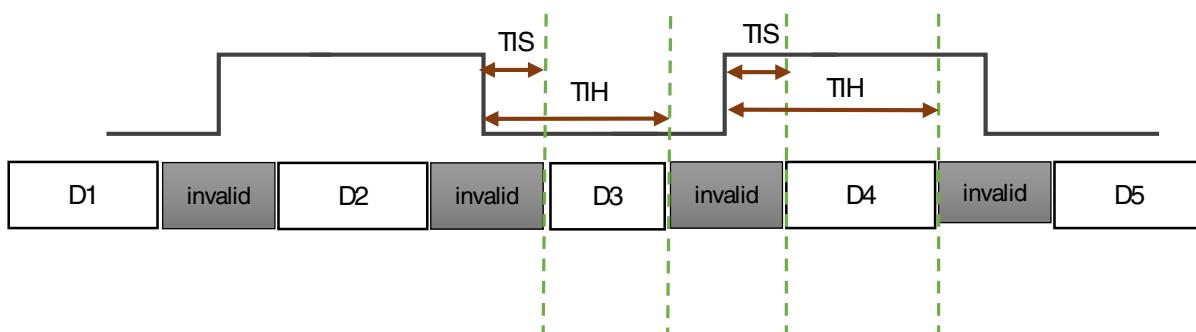


Figure 10. QuadSPI output timing (SDR mode) diagram



TIS – Setup Time

TIH – Hold Time

Figure 11. QuadSPI input timing (HyperRAM mode) diagram

ADC electrical specifications

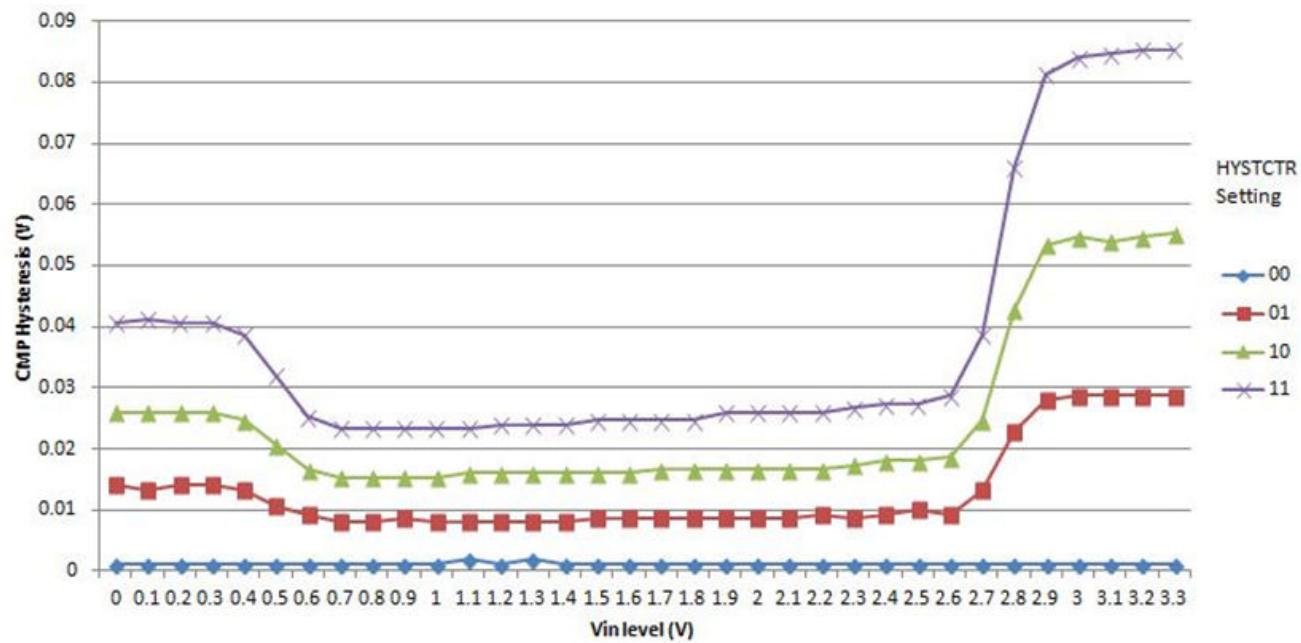


Figure 14. Typical hysteresis vs. Vin level (VDDA = 3.3 V, PMODE = 0)

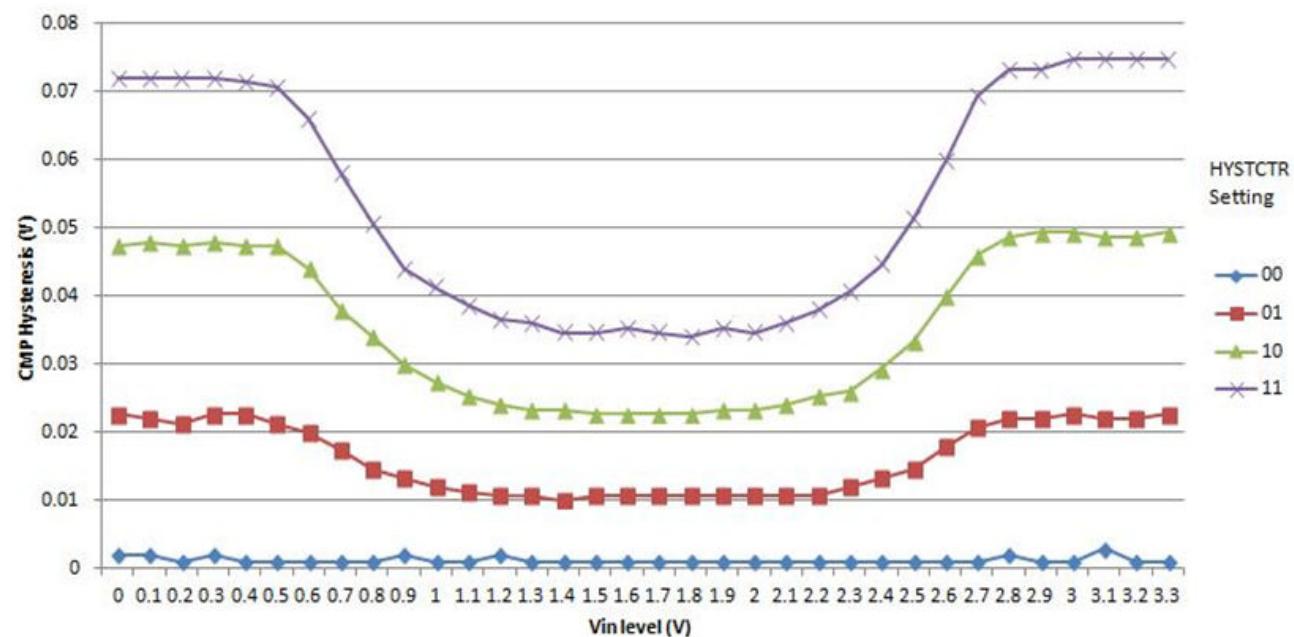
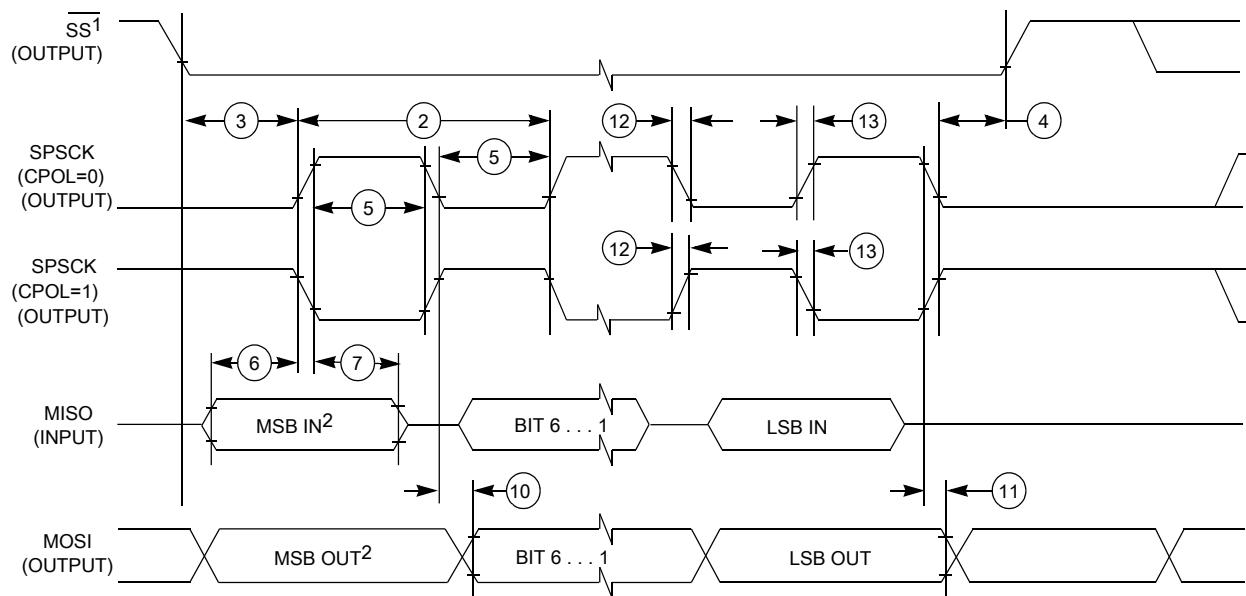
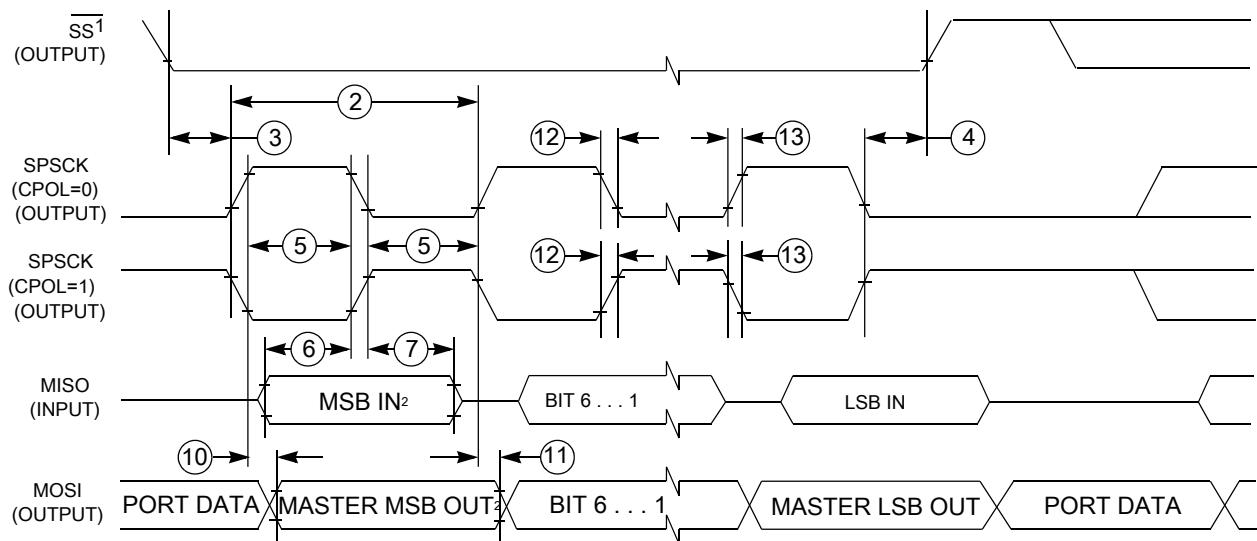


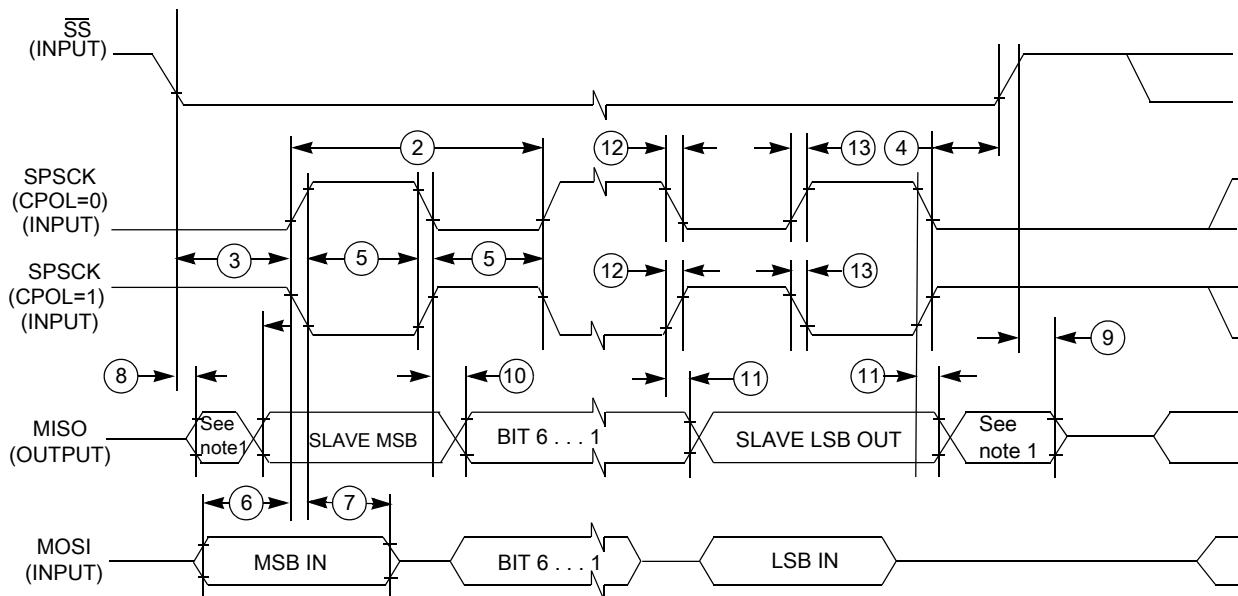
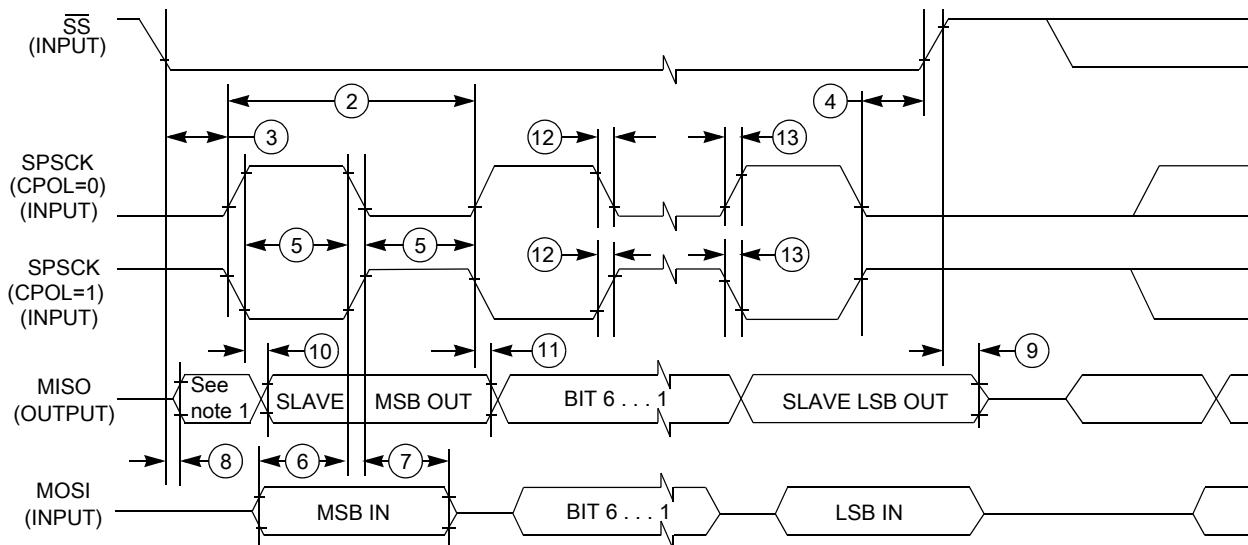
Figure 15. Typical hysteresis vs. Vin level (VDDA = 3.3 V, PMODE = 1)

Table 32. LPSPI electrical specifications¹ (continued)

Num	Symbol	Description	Conditions	Run Mode ²				HSRUN Mode ²				VLPR Mode				Unit	Communication modules		
				5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO					
				Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.				
4	t _{Lag} ⁹	Enable lag time (After SPSCK delay)	Slave	-	-	-	-	-	-	-	-	-	-	-	-	ns	Communication modules		
			Master	-	-	-	-	-	-	-	-	-	-	-	-	ns	Communication modules		
			Master Loopback ⁵	-	-	-	-	-	-	-	-	-	-	-	-	ns	Communication modules		
			Master Loopback(slow) ⁶	-	-	-	-	-	-	-	-	-	-	-	-	ns	Communication modules		
5	t _{WSPSCK} ¹⁰	Clock(SPSCK) high or low time (SPSCK duty cycle)	Slave	-	-	-	-	-	-	-	-	-	-	-	-	ns	Communication modules		
			Master	-	-	-	-	-	-	-	-	-	-	-	-	ns	Communication modules		
			Master Loopback ⁵	-	-	-	-	-	-	-	-	-	-	-	-	ns	Communication modules		
			Master Loopback(slow) ⁶	-	-	-	-	-	-	-	-	-	-	-	-	ns	Communication modules		
6	t _{SU}	Data setup time(inputs)	Slave	3	-	5	-	3	-	5	-	18	-	18	-	ns	Communication modules		
			Master	29	-	38	-	26	-	37 ¹¹ 32 ¹²	-	72	-	78	-	ns	Communication modules		
			Master Loopback ⁵	7	-	8	-	5	-	7	-	20	-	20	-	ns	Communication modules		
			Master Loopback(slow) ⁶	8	-	10	-	7	-	9	-	20	-	20	-	ns	Communication modules		
7	t _{Hl}	Data hold time(inputs)	Slave	3	-	3	-	3	-	3	-	14	-	14	-	ns	Communication modules		
			Master	0	-	0	-	0	-	0	-	0	-	0	-	ns	Communication modules		
			Master Loopback ⁵	3	-	3	-	2	-	3	-	11	-	11	-	ns	Communication modules		
			Master Loopback(slow) ⁶	3	-	3	-	3	-	3	-	12	-	12	-	ns	Communication modules		

Table continues on the next page...

**Figure 18. LPSPI master mode timing (CPHA = 0)****Figure 19. LPSPI master mode timing (CPHA = 1)**

**Figure 20. LPSPI slave mode timing (CPHA = 0)****Figure 21. LPSPI slave mode timing (CPHA = 1)**

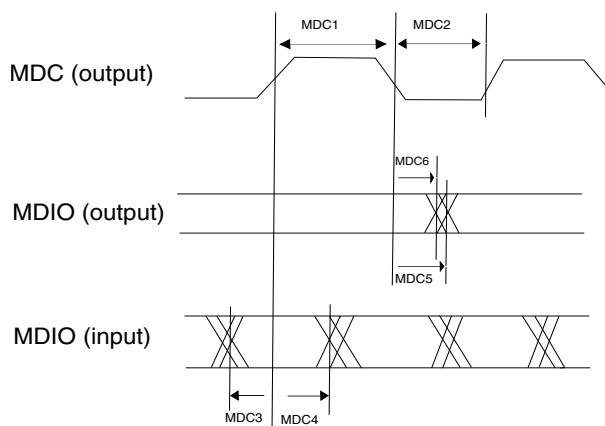
6.5.3 LPI2C electrical specifications

See [General AC specifications](#) for LPI2C specifications.

For supported baud rate see section 'Chip-specific LPI2C information' of the *Reference Manual*.

Table 37. MDIO timing specifications (continued)

Symbol	Description	Min.	Max.	Unit
MDC1	MDC pulse width high	40%	60%	MDC period
MDC2	MDC pulse width low	40%	60%	MDC period
MDC3	MDIO (input) to MDC rising edge setup	25	—	ns
MDC4	MDIO (input) to MDC rising edge hold	0	—	ns
MDC5	MDC falling edge to MDIO output valid (maximum propagation delay)	—	25	ns
MDC6	MDC falling edge to MDIO output invalid (minimum propagation delay)	-10	—	ns

**Figure 28. MII/RMII serial management channel timing diagram**

6.5.7 Clockout frequency

Maximum supported clock out frequency for this device is 20 MHz

6.6 Debug modules

6.6.1 SWD electrical specofications

Table 40. JTAG electrical specifications

Symbol	Description	Run Mode				HSRUN Mode				VLPR Mode				Unit	
		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO			
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
J1	TCLK frequency of operation													MHz	
	Boundary Scan	-	20	-	20	-	20	-	20	-	10	-	10		
	JTAG	-	20	-	20	-	20	-	20	-	10	-	10		
J2	TCLK cycle period	1/J1	-	1/J1	-	1/J1	-	1/J1	-	1/J1	-	1/J1	-	ns	
J3	TCLK clock pulse width													ns	
	Boundary Scan	5	5	5	5	5	5	5	5	5	5	5	5		
	JTAG	J2/Z + 5	J2/Z - 5	J2/Z + 5	J2/Z - 5	J2/Z + 5	J2/Z - 5	J2/Z + 5	J2/Z - 5	J2/Z + 5	J2/Z - 5	J2/Z + 5	J2/Z - 5		
J4	TCLK rise and fall times	-	1	-	1	-	1	-	1	-	1	-	1	ns	
J5	Boundary scan input data setup time to TCLK rise	5	-	5	-	5	-	5	-	5	-	15	-	ns	
J6	Boundary scan input data hold time after TCLK rise	5	-	5	-	5	-	5	-	5	-	8	-	ns	
J7	TCLK low to boundary scan output data valid	-	28	-	32	-	28	-	32	-	80	-	80	ns	
J8	TCLK low to boundary scan output data invalid	0	-	0	-	0	-	0	-	0	-	0	-		
J9	TCLK low to boundary scan output high-Z	-	28	-	32	-	28	-	32	-	80	-	80	ns	
J10	TMS, TDI input data setup time to TCLK rise	3	-	3	-	3	-	3	-	15	-	15	-	ns	
J11	TMS, TDI input data hold time after TCLK rise	2	-	2	-	2	-	2	-	8	-	8	-	ns	
J12	TCLK low to TDO data valid	-	28	-	32	-	28	-	32	-	80	-	80	ns	
J13	TCLK low to TDO data invalid	0	-	0	-	0	-	0	-	0	-	0	-	ns	
J14	TCLK low to TDO high-Z	-	28	-	32	-	28	-	32	-	80	-	80	ns	

Table 42. Thermal characteristics for the 100 MAPBGA package

Rating	Conditions	Symbol	Values			Unit
			S32K146	S32K144	S32K148	
Thermal resistance, Junction to Ambient (Natural Convection) ^{1, 2}	Single layer board (1s)	R _{θJA}	57.2	61.0	52.5	°C/W
Thermal resistance, Junction to Ambient (Natural Convection) ^{1, 2, 3}	Four layer board (2s2p)	R _{θJA}	32.1	35.6	27.5	°C/W
Thermal resistance, Junction to Ambient (@200 ft/min) ^{1, 2, 3}	Single layer board (1s)	R _{θJMA}	44.1	46.6	39.0	°C/W
Thermal resistance, Junction to Ambient (@200 ft/min) ^{1, 3}	Two layer board (2s2p)	R _{θJMA}	27.2	30.9	22.8	°C/W
Thermal resistance, Junction to Board ⁴	—	R _{θJB}	15.3	18.9	11.2	°C/W
Thermal resistance, Junction to Case ⁵	—	R _{θJC}	10.2	14.2	7.5	°C/W
Thermal resistance, Junction to Package Top outside center ⁶	—	Ψ _{JT}	0.2	0.4	0.2	°C/W
Thermal resistance, Junction to Package Bottom outside center ⁷	—	Ψ _{JB}	12.2	15.9	18.3	°C/W

1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per SEMI G38-87 and JEDEC JESD51-2 with the single layer board horizontal.
3. Per JEDEC JESD51-6 with the board horizontal.
4. Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JT.
7. Thermal characterization parameter indicating the temperature difference between package bottom center and the junction temperature per JEDEC JESD51-12. When Greek letters are not available, the thermal characterization parameter is written as Psi-JB.

Table 43. Revision History (continued)

Rev. No.	Date	Substantial Changes
		<ul style="list-style-type: none"> • Fixed the typo in R_{SW1} • In LPSPI electrical specifications : <ul style="list-style-type: none"> • Updated t_{Lead} and t_{Lag} • Added footnote in Figure: LPSPI slave mode timing ($CPHA = 0$) and Figure: LPSPI slave mode timing ($CPHA = 1$) • In Thermal characteristics : <ul style="list-style-type: none"> • Updated the name of table: Thermal characteristics for 32-pin QFN and 48/64/100/144/176-pin LQFP package • Deleted specs for $R_{\theta JC}$ for 32 QFN package • Added '$R_{\theta JCBottom}$'
8	18 June 2018	<ul style="list-style-type: none"> • In attachment 'S32K1xx_Power_Modes_Configuration': <ul style="list-style-type: none"> • Updated VLPR peripherals disabled and Peripherals Enabled use case #1, using 4 MHz for System clock, 2 MHz for bus clock, and 1MHz for flash. • Removed S32K116 from Notes • In figure: S32K1xx product series comparison : <ul style="list-style-type: none"> • Added note 'Availability of peripherals depends on the pin availability ...' • Updated 'Ambient Operation Temperature' row • Updated 'System RAM (including FlexRAM and MTB)' row for S32K144, S32K146, and S32K148 • In Ordering information : <ul style="list-style-type: none"> • Updated figure for 'Y: Optional feature' • Updated footnote 3 • In Power and ground pins : <ul style="list-style-type: none"> • In figure 'Power diagram', updated V_{Flash} frequency to 3.3 V • In Power mode transition operating behaviors : <ul style="list-style-type: none"> • Updated footnote for 'VLPS Mode: All clock sources disabled' • In Power consumption : <ul style="list-style-type: none"> • Added IDDs for S32K116 • Added VLPR Peripherals enabled use case 2 at 125 °C/Typicals • Renamed VLPR 'Peripherals enabled' to 'Peripherals enabled use case 1' • Added footnote 'Data collected using RAM' to VLPR 'Peripherals disabled' and VLPR 'Peripherals enabled use case 1' • Updated VLPS Peripherals enabled at 25 °C/Typicals for S32K142 and S32K144 to 40 μA and 42 μA respectively • Added table 'VLPS additional use-case power consumption at typical conditions' • In DC electrical specifications at 3.3 V Range : <ul style="list-style-type: none"> • Updated naming conventions • Added specs for GPIO-FAST pad • In DC electrical specifications at 5.0 V Range : <ul style="list-style-type: none"> • Updated naming conventions • Added specs for GPIO-FAST pad • In AC electrical specifications at 3.3 V range : <ul style="list-style-type: none"> • Updated naming conventions • Added specs for GPIO-FAST pad • In AC electrical specifications at 5 V range : <ul style="list-style-type: none"> • Updated naming conventions • Added specs for GPIO-FAST pad • In External System Oscillator electrical specifications : <ul style="list-style-type: none"> • Clarified description of g_{mXosc} • Updated V_{IL} max. to 1.15 V • In Fast internal RC Oscillator (FIRC) electrical specifications :